

SEMiX603GAL17E4p



SEMiX® 3p

Trench IGBT Modules

SEMiX603GAL17E4p

Features*

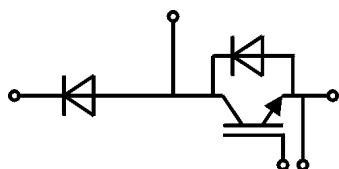
- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$ with positive temperature coefficient
- High short circuit capability
- Press-fit pins as auxiliary contacts
- UL recognized, file no. E63532

Typical Applications

- AC inverter drives
- UPS
- Renewable energy systems

Remarks

- Product reliability results are valid for $T_j = 150^\circ\text{C}$
- V_{isol} between temperature sensor and power section is only 2500V
- For storage and case temperature with TIM see document "TP(*) SEMiX 3p"



GAL

Absolute Maximum Ratings

Symbol	Conditions	Values	Unit
IGBT			
V_{CES}	$T_j = 25^\circ\text{C}$	1700	V
I_C	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	835
		$T_c = 80^\circ\text{C}$	638
I_{Cnom}		600	A
I_{CRM}		1800	A
V_{GES}		-20 ... 20	V
t_{psc}	$V_{CC} = 1000\text{ V}$ $V_{GE} \leq 15\text{ V}$ $V_{CES} \leq 1700\text{ V}$	$T_j = 150^\circ\text{C}$	10
T_j		-40 ... 175	$^\circ\text{C}$

Inverse diode

V_{RRM}	$T_j = 25^\circ\text{C}$	1700	V
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	736
		$T_c = 80^\circ\text{C}$	542
I_{FRM}		1200	A
I_{FSM}	$t_p = 10\text{ ms, sin } 180^\circ, T_j = 25^\circ\text{C}$	3510	A
T_j		-40 ... 175	$^\circ\text{C}$

Freewheeling diode

V_{RRM}	$T_j = 25^\circ\text{C}$	1700	V
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	703
		$T_c = 80^\circ\text{C}$	517
I_{FRM}		1200	A
I_{FSM}	$t_p = 10\text{ ms, sin } 180^\circ, T_j = 25^\circ\text{C}$	3510	A
T_j		-40 ... 175	$^\circ\text{C}$

Module

$I_{t(RMS)}$		600	A
T_{stg}	module without TIM	-40 ... 125	$^\circ\text{C}$
V_{isol}	AC sinus 50Hz, $t = 1\text{ min}$	4000	V

Characteristics

Symbol	Conditions	min.	typ.	max.	Unit
IGBT					
$V_{CE(sat)}$	$I_C = 600\text{ A}$ $V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	1.95	2.30	V
		$T_j = 150^\circ\text{C}$	2.48	2.80	V
V_{CE0}	chipelevel	$T_j = 25^\circ\text{C}$	1.02	1.20	V
		$T_j = 150^\circ\text{C}$	0.92	1.03	V
r_{CE}	$V_{GE} = 15\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	1.55	1.83	m Ω
		$T_j = 150^\circ\text{C}$	2.6	3.0	m Ω
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 24\text{ mA}$	5.2	5.8	6.2	V
I_{CES}	$V_{GE} = 0\text{ V}, V_{CE} = 1700\text{ V}, T_j = 25^\circ\text{C}$			5	mA
C_{ies}	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$	46.5		nF
C_{oes}		$f = 1\text{ MHz}$	1.98		nF
C_{res}		$f = 1\text{ MHz}$	1.65		nF
Q_G	$V_{GE} = -8\text{ V...} + 15\text{ V}$		4800		nC
R_{Gint}	$T_j = 25^\circ\text{C}$		1.1		Ω



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Typical Applications

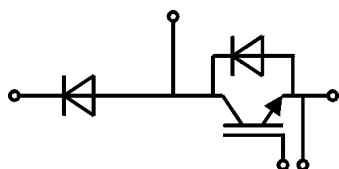
- AC inverter drives
- UPS
- Renewable energy systems

Remarks

- Product reliability results are valid for $T_j=150^\circ\text{C}$
- V_{isol} between temperature sensor and power section is only 2500V
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Characteristics

Symbol	Conditions	min.	typ.	max.	Unit
IGBT					
$t_{d(on)}$	$V_{CC} = 900\text{ V}$ $I_C = 600\text{ A}$ $T_j = 150^\circ\text{C}$		245		ns
t_r	$V_{GE} = +15/-15\text{ V}$ $T_j = 150^\circ\text{C}$		85		ns
E_{on}	$R_{G\ on} = 2.4\ \Omega$ $T_j = 150^\circ\text{C}$		132		mJ
$t_{d(off)}$	$R_{G\ off} = 1\ \Omega$ $T_j = 150^\circ\text{C}$		710		ns
t_f	$di/dt_{on} = 7900\text{ A}/\mu\text{s}$ $di/dt_{off} = 3000\text{ A}/\mu\text{s}$ $T_j = 150^\circ\text{C}$		170		ns
E_{off}	$dv/dt = 3500\text{ V}/\mu\text{s}$ $L_s = 25\text{ nH}$ $T_j = 150^\circ\text{C}$		213		mJ
$R_{th(j-c)}$	per IGBT			0.049	K/W
$R_{th(c-s)}$	per IGBT ($\lambda_{grease}=0.81\text{ W}/(\text{m}^2\text{K})$)		0.033		K/W
$R_{th(c-s)}$	per IGBT, pre-applied phase change material		0.023		K/W
Inverse diode					
$V_F = V_{EC}$	$I_F = 600\text{ A}$ $V_{GE} = 0\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	1.88	2.23	V
		$T_j = 150^\circ\text{C}$	1.95	2.32	V
V_{F0}	chipelevel	$T_j = 25^\circ\text{C}$	1.32	1.56	V
		$T_j = 150^\circ\text{C}$	1.08	1.22	V
r_F	chipelevel	$T_j = 25^\circ\text{C}$	0.93	1.12	m Ω
		$T_j = 150^\circ\text{C}$	1.45	1.83	m Ω
I_{RRM}	$I_F = 600\text{ A}$ $di/dt_{off} = 8000\text{ A}/\mu\text{s}$ $T_j = 150^\circ\text{C}$		700		A
Q_{rr}	$V_{GE} = -15\text{ V}$ $T_j = 150^\circ\text{C}$		190		μC
E_{rr}	$V_{CC} = 900\text{ V}$ $T_j = 150^\circ\text{C}$		125		mJ
$R_{th(j-c)}$	per diode			0.082	K/W
$R_{th(c-s)}$	per diode ($\lambda_{grease}=0.81\text{ W}/(\text{m}^2\text{K})$)		0.038		K/W
$R_{th(c-s)}$	per diode, pre-applied phase change material		0.030		K/W
Freewheeling diode					
$V_F = V_{EC}$	$I_F = 600\text{ A}$ $V_{GE} = 0\text{ V}$ chipelevel	$T_j = 25^\circ\text{C}$	1.88	2.23	V
		$T_j = 150^\circ\text{C}$	1.95	2.32	V
V_{F0}	chipelevel	$T_j = 25^\circ\text{C}$	1.32	1.56	V
		$T_j = 150^\circ\text{C}$	1.08	1.22	V
r_F	chipelevel	$T_j = 25^\circ\text{C}$	0.93	1.12	m Ω
		$T_j = 150^\circ\text{C}$	1.45	1.83	m Ω
I_{RRM}	$I_F = 600\text{ A}$ $di/dt_{off} = 8000\text{ A}/\mu\text{s}$ $T_j = 150^\circ\text{C}$		700		A
Q_{rr}	$V_{GE} = -15\text{ V}$ $T_j = 150^\circ\text{C}$		190		μC
E_{rr}	$V_{CC} = 900\text{ V}$ $T_j = 150^\circ\text{C}$		125		mJ
$R_{th(j-c)}$	per diode			0.088	K/W
$R_{th(c-s)}$	per diode ($\lambda_{grease}=0.81\text{ W}/(\text{m}^2\text{K})$)		0.038		K/W
$R_{th(c-s)}$	per diode, pre-applied phase change material		0.030		K/W



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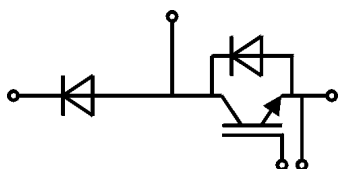
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Remarks

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Characteristics

Symbol	Conditions	min.	typ.	max.	Unit
Module					
L_{CE}			20		nH
$R_{CC'+EE'}$	measured per switch	$T_C = 25^\circ\text{C}$	0.95		mΩ
		$T_C = 125^\circ\text{C}$	1.25		mΩ
$R_{th(c-s)1}$	calculated without thermal coupling		0.009		K/W
$R_{th(c-s)2}$	including thermal coupling, T_s underneath module ($\lambda_{grease}=0.81\text{ W/(m}^2\text{K)}$)		0.014		K/W
$R_{th(c-s)2}$	including thermal coupling, T_s underneath module, pre-applied phase change material		0.021		K/W
M_s	to heat sink (M5)	3		6	Nm
M_t					
	to terminals (M6)	3		6	Nm
					Nm
w				350	g
Temperature Sensor					
R_{100}	$T_C=100^\circ\text{C}$ ($R_{25}=5\text{ k}\Omega$)		$493 \pm 5\%$		Ω
$B_{100/125}$	$R_{(T)}=R_{100}\exp[B_{100/125}(1/T-1/T_{100})]$; $T[K]$		$3550 \pm 2\%$		K



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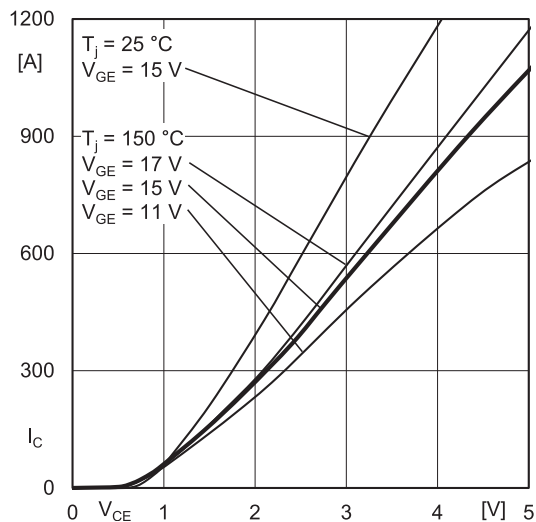


Fig. 1: Typ. output characteristic, inclusive $R_{CC'+EE'}$

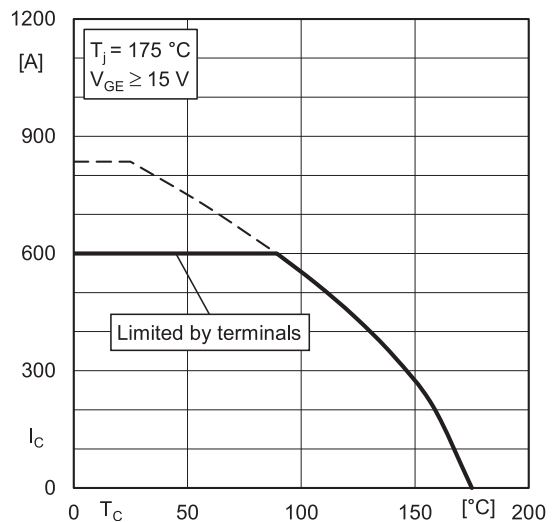


Fig. 2: Rated current vs. temperature $I_C = f(T_C)$

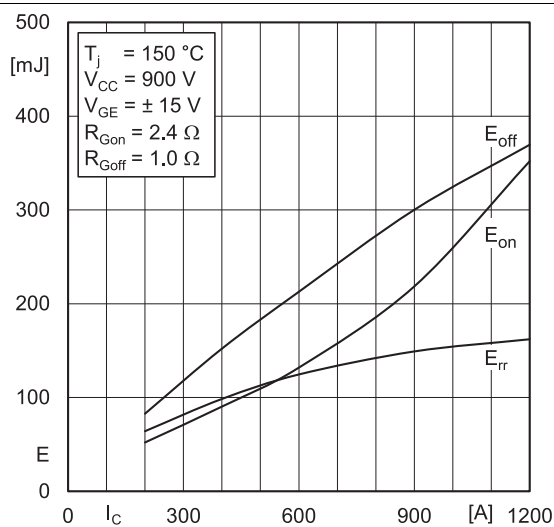


Fig. 3: Typ. turn-on /-off energy = $f(I_C)$

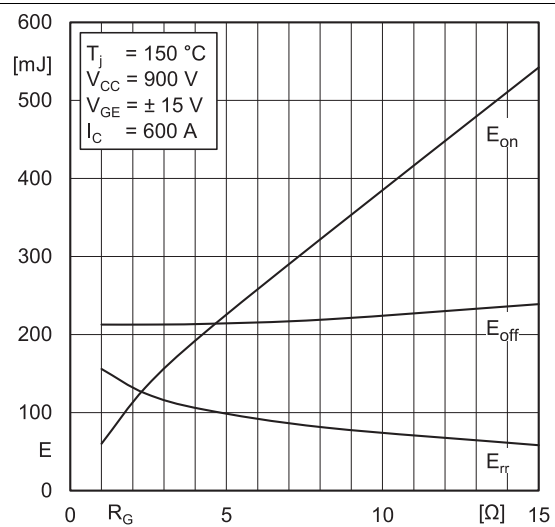


Fig. 4: Typ. turn-on /-off energy = $f(R_G)$

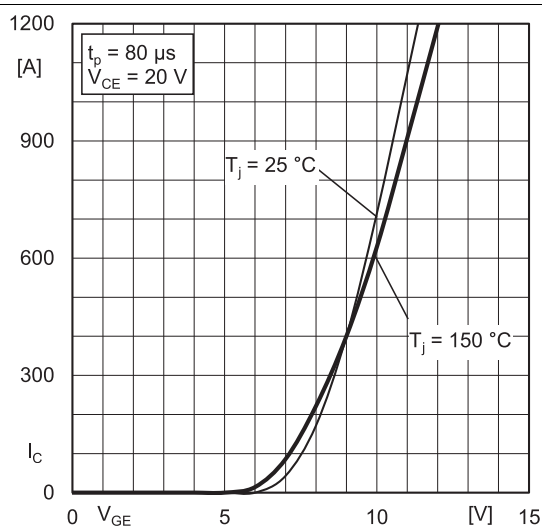


Fig. 5: Typ. transfer characteristic

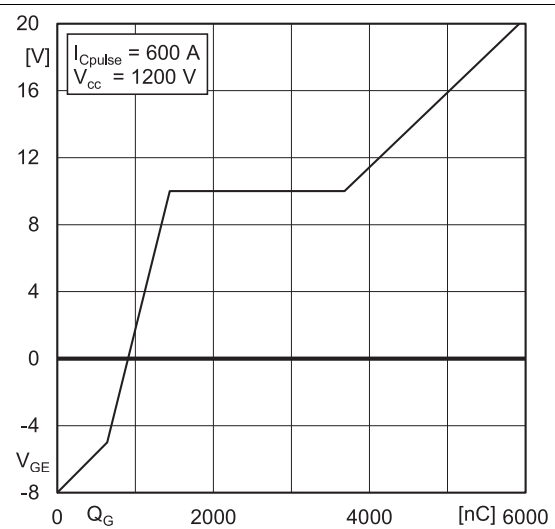


Fig. 6: Typ. gate charge characteristic

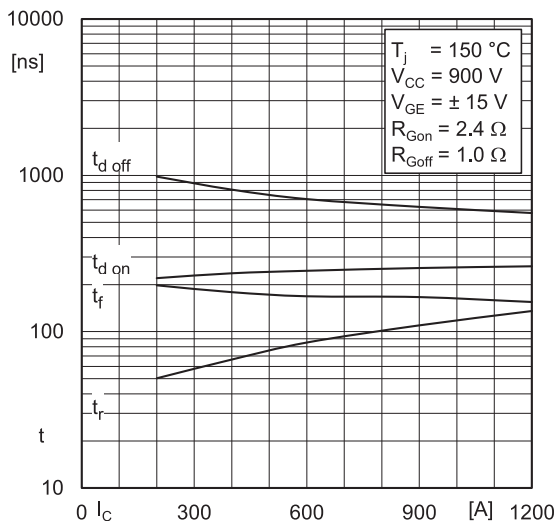


Fig. 7: Typ. switching times vs. I_C

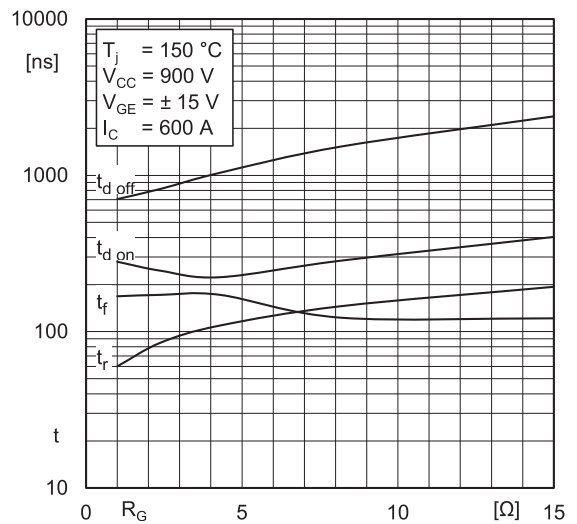


Fig. 8: Typ. switching times vs. gate resistor R_G

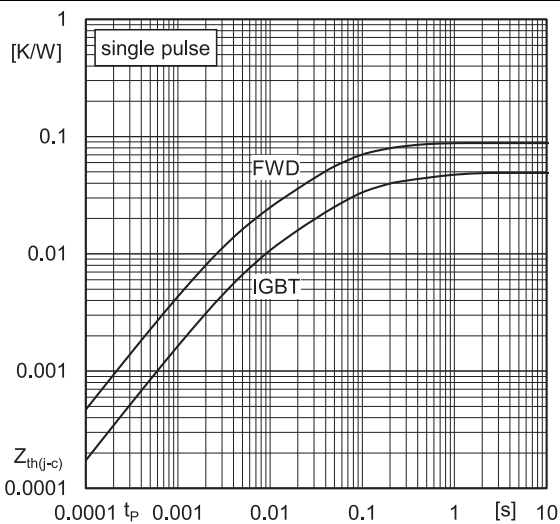


Fig. 9: Transient thermal impedance

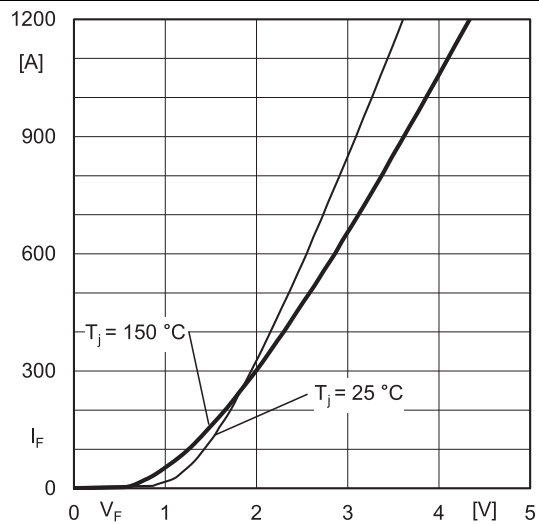


Fig. 10: Typ. CAL diode forward charact., incl. $R_{CC'+EE'}$

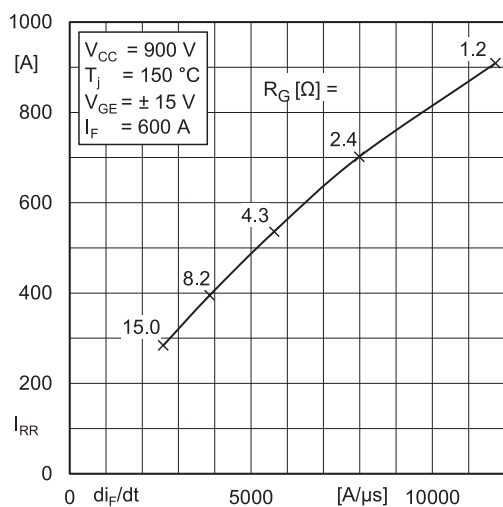


Fig. 11: Typ. CAL diode peak reverse recovery current

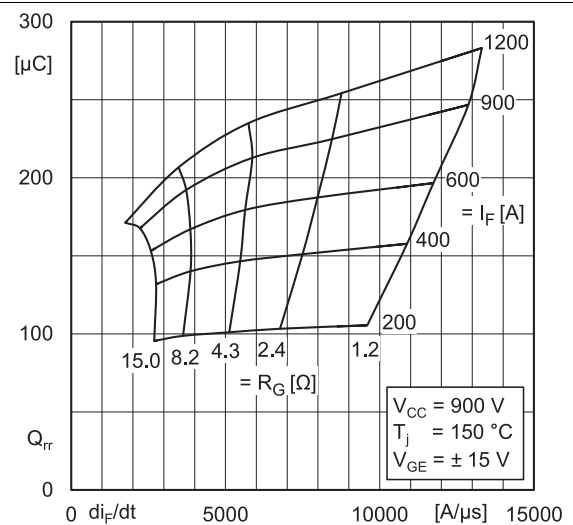


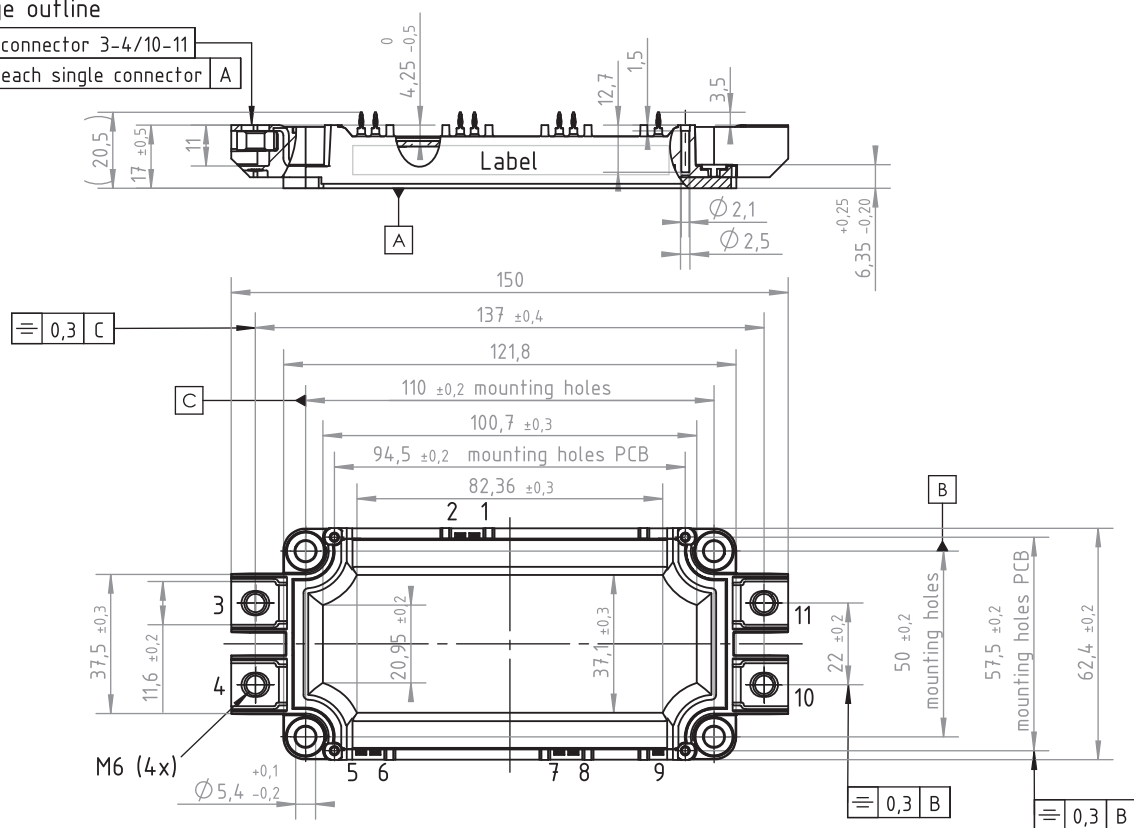


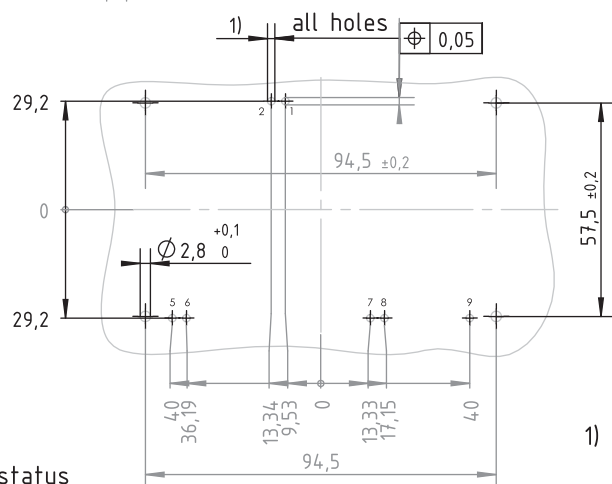
Fig. 12: Typ. CAL diode recovery charge

Package outline

	0,3 connector 3-4/10-11	
	0,2 each single connector	A



PCB drillhole pattern

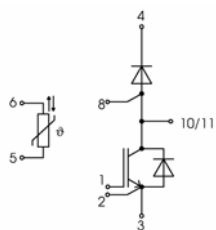


Dimensions in mm

Dimensions valid in mounted status

1) PCB hole specification see
Mounting Instructions SEMiX press-fit

SEMIX 3p



pinout

This is an electrostatic discharge sensitive device (ESDS) due to international standard IEC 61340.

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